

Modelling of the Coulombic centres charge emission: electric field approximation comparison in simulating the measured TSC signal

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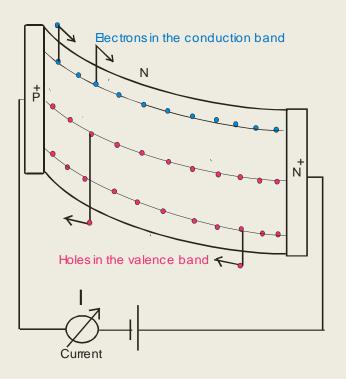


Outline

- Basic TSC introduction, standard approach (non-Coulombic defect centres)
- Coulombic centres (e.g. B_iO_i, H116K, H152K...)
 - General Poole-Frenkel theory
 - Electric field approximations
- Results and comparisons of different approaches
- Conclusions



TSC basics: standard approach



- ✓ The sample is cooled at low temperatures (10 K or below)
- Charge is injected into defect traps using an applied electrical field.
- ✓ A reverse bias larger than the depletion bias (such that the space charge region covers the entire volume) is applied (full depletion regime).
- The sample is heated with a constant heating rate and the emission current is measured.





TSC basics: standard approach

$$I_{TSC}(T) = \frac{q \, A \, d}{2} \, e_n(T) \, n_{traps}(T)$$

$$n_{traps}(T) = n_{traps}(T_0) \exp\left(-\int_{T_0}^T \frac{1}{\beta} e_n(T') dT'\right)$$

 $e_n(T)$ - the emission rate for electrons with a constant activation energy (E_a) (not dependent on the electric field!)

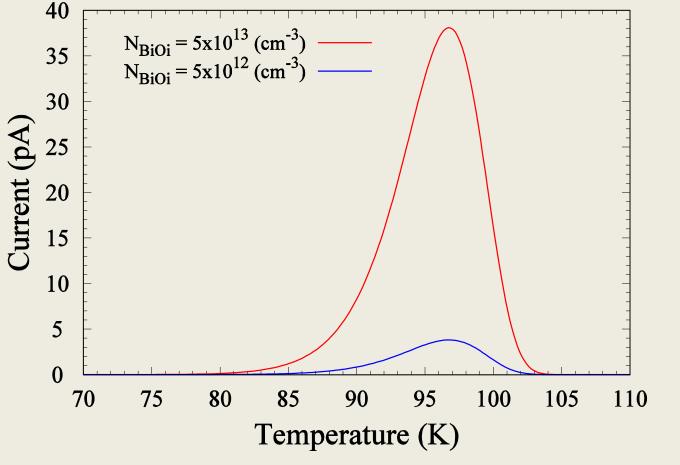
 $n_{traps}(T_0)$ - density of filled traps at T_0

✓ No charge recombination is considered in the active region



TSC basics: standard approach

TSC current for BiOi defect no Poole-Frenkel



 $\sigma_n = 1.05 \times 10^{-14} \text{ cm}^2$

$$E_a = 0.25 (eV)$$





- $\mathbf{E}_{\mathbf{a}} \neq \mathbf{constant}! \mathbf{E}_{\mathbf{a}}$ is dependent on the electric field F(x) in the active region.
- $E_{a}^{0}(F=0) > E_{a}(F \neq 0)$
- *Poole- Frenkel emission mechanism* must be used
- F(x) as for an abrupt junction must be considered as well
- F(x) depend on the doping of the device (charge density)

F(x) > F(x) = F(x) Is essentially unknown Approximations must be used

Which approach should be used?





I. <u>Charge density at room temperature Na=[Bs]</u>

• Poisson equation is solved for the uniform effective

charge density at room temperature.

$$\left| \begin{smallmatrix} p & & \ n^+ & ext{active region} & \ ext{inform distribution of defects} \end{smallmatrix}
ight|^p F(x) = rac{q \ N_a}{arepsilon} \left(d-x
ight) + rac{V-V_{depletion}}{d}$$

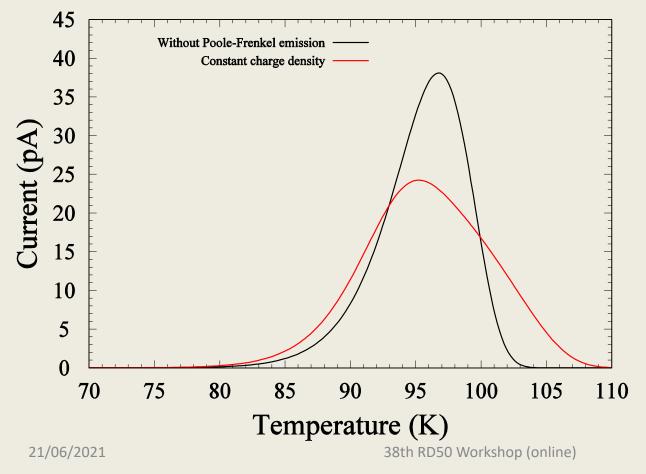
 $N_a = \text{Boron doping concentration } ([B_s])$





$$F(x) = \frac{q N_a}{\varepsilon} \left(d - x \right) + \frac{V - V_{depletion}}{d}$$

TSC current BiOi defect



 $N_{a} = 1 \times 10^{14} \text{ (cm}^{-3})$ $n_{BiOi} = 5 \times 10^{13} \text{ (cm}^{-3})$ V = 190 (V) $\sigma_{n} = 1.05 \times 10^{-14} \text{ cm}^{2}$ $E_{a} = 0.25 \text{ (eV)}$ $E_{a}^{0} = 0.28 \text{ (eV)}$





II. <u>Temperature dependent charge density</u>

- Poisson equation is used to calculate the electric field for a uniform charge distribution.
- The field for the current temperature step is calculated using the charge density from the previous temperature step.

$$N_{eff}(T) = N_a - 2 \cdot N_{BiOi} + n_{BiOi}(T)$$





$$F(x,T) = \frac{q N_{eff}(T)}{\varepsilon} \left(d - x\right) + \frac{V - V_{depletion}(T)}{d}$$

Electron activation energy without an applied field! (generally very difficult to obtain and impossible to measure!)

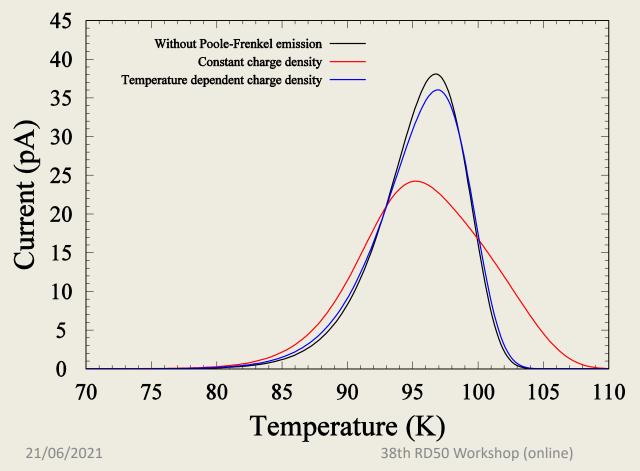
$$\begin{split} n_{BiOi}(T) = &N_{BiOi} \frac{1}{d} \int_{0}^{d} exp \left[-\frac{1}{\beta} \int_{T_{0}}^{T} \sigma_{n} \nu_{th}(t) Nc(t) e^{-\frac{E_{a}^{0}}{k_{B} t}} \times \right. \\ & \times \left[\left(\frac{k_{B} t}{q} \sqrt{\frac{q F(x,T)}{\pi \varepsilon}} \right)^{2} \left(e^{\frac{q}{k_{B} t} \sqrt{\frac{q F(x,T)}{\pi \varepsilon}}} \left(-1 + \frac{q}{k_{B} t} \sqrt{\frac{q F(x,T)}{\pi \varepsilon}} \right) + 1 \right) + \frac{1}{2} \right] dt \right] dx \end{split}$$





$$F(x,T) = \frac{q N_{eff}(T)}{\varepsilon} \left(d - x\right) + \frac{V - V_{depletion}(T)}{d}$$

TSC current BiOi defect



$$N_{a} = 1 \times 10^{14} \text{ (cm}^{-3}\text{)}$$

$$n_{BiOi} = 5 \times 10^{13} \text{ (cm}^{-3}\text{)}$$

$$V = 190 \text{ (V)}$$

$$\sigma_{n} = 1.05 \times 10^{-14} \text{ cm}^{2}$$

$$E_{a} = 0.25 \text{ (eV)}$$

$$E_{a}^{0} = 0.28 \text{ (eV)}$$



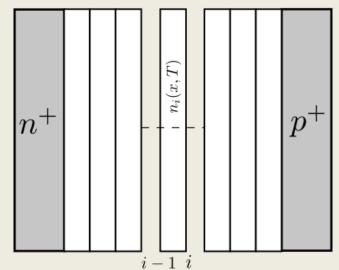


Results: electric field approximations $\sum^{N_x} n_i(T)$

III. Finite element approach

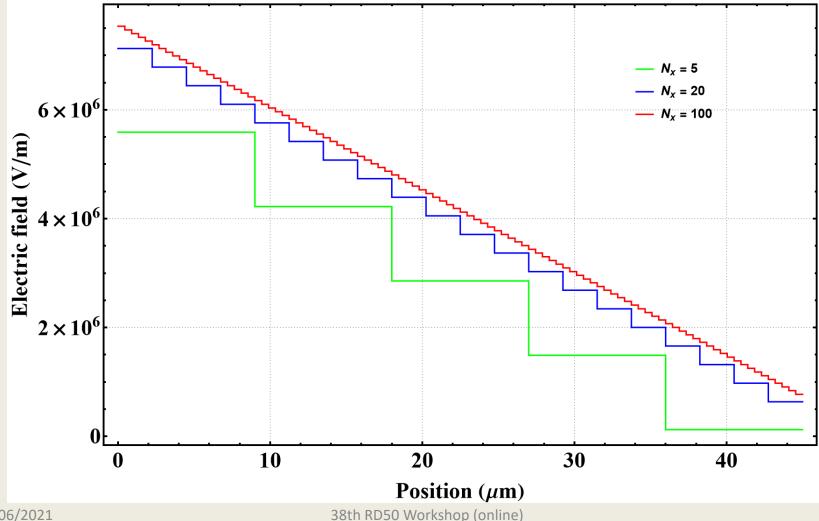
- $N_{eff}(T) = \frac{1}{N_x}$ • Active region is split in a number N_r of equal slices.
- The charge density is uniform in each slice at each temperature step.
- The electric field is calculated in each slice at each temperature step.
- Continuity conditions are imposed at the interfaces between neighbouring slices.
- No charge recombination is considered in the active region

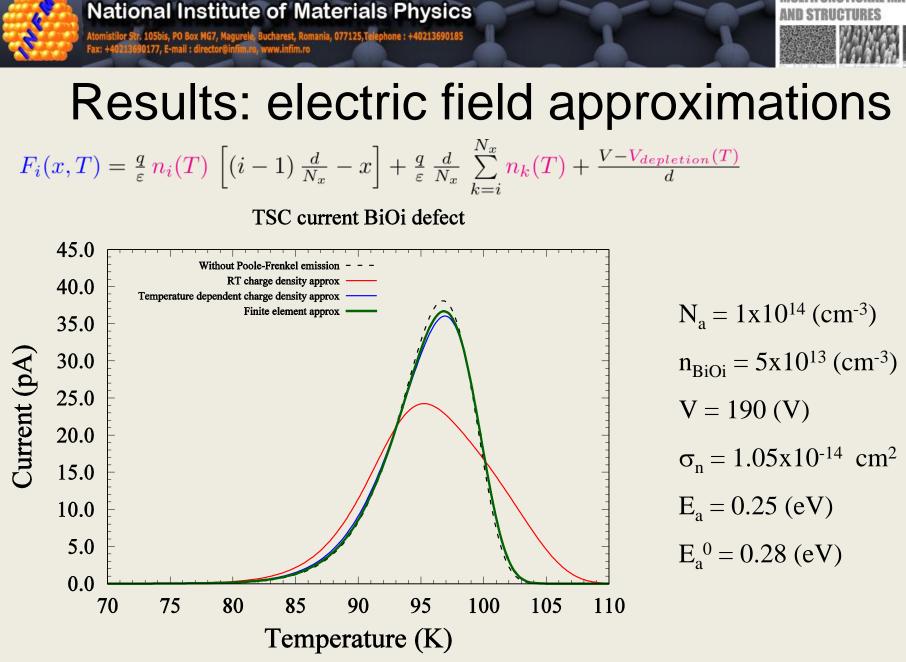
 $F_i(x)$



$$F_i(x,T) = \frac{q}{\varepsilon} n_i(T) \left[(i-1) \frac{d}{N_x} - x \right] + \frac{q}{\varepsilon} \frac{d}{N_x} \sum_{k=i}^{N_x} n_k(T) + \frac{V - V_{depletion}(T)}{d}$$





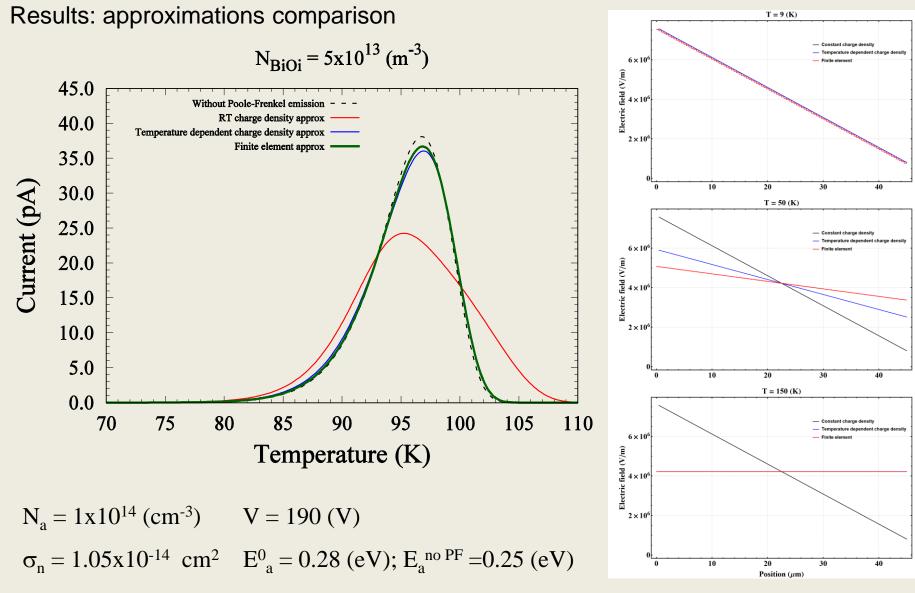


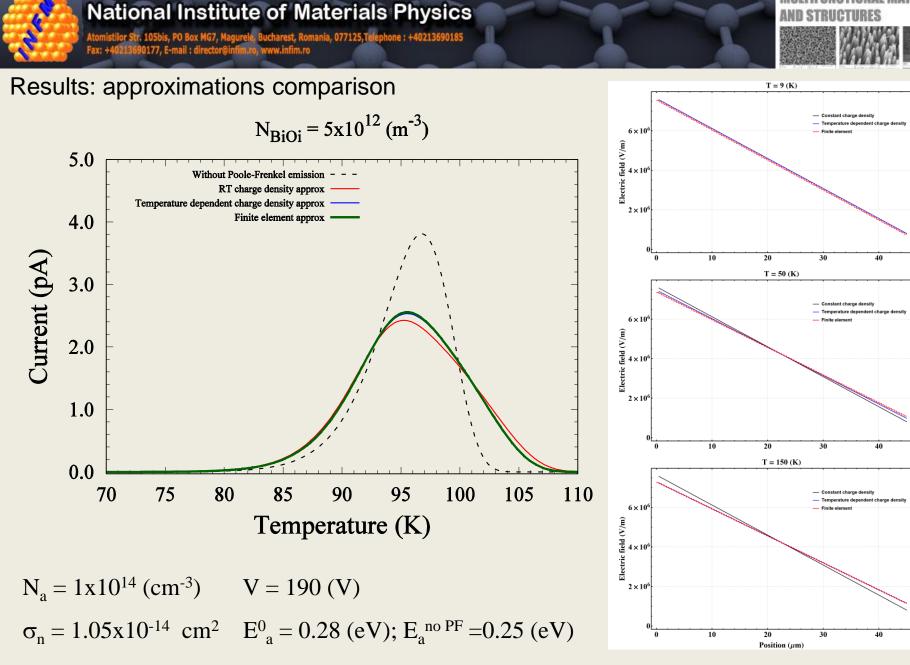
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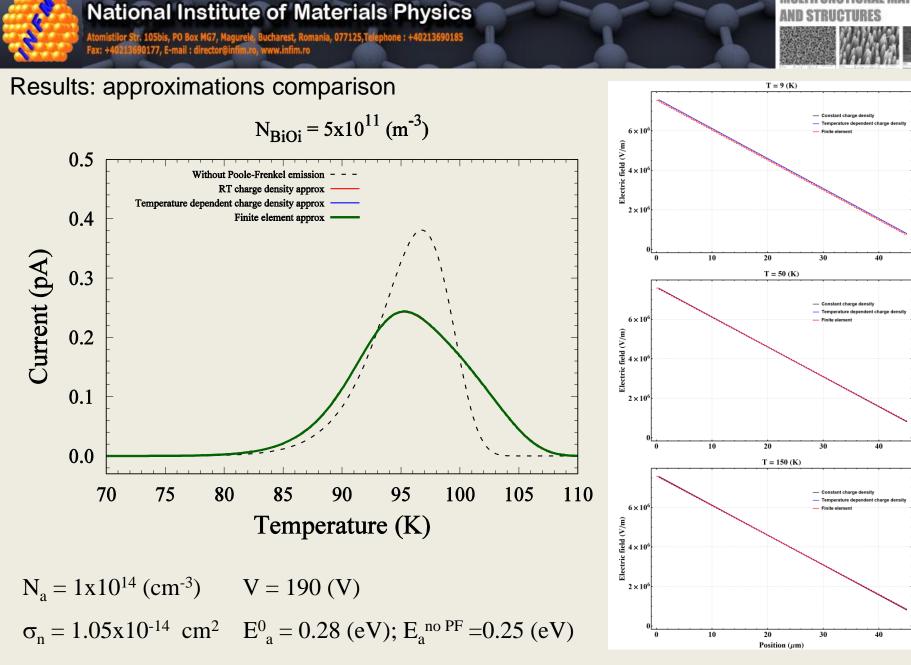






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Summary and Conclusions

- TSC evaluations of Coulombic centers induced by irradiation BiOi as example
- Poole-Frenckel formalism was accounted
- Three approximations for the electric field were investigated
- For low defect concentrations all approximations give the same result
- Differences appear for high [BiOi]



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